

## **NTC SERIES**

### TANTALUM CHIP CAPACITORS

- FAILURE RATE ESTIMATION
- DE-RATED OPERATION
- LIST OF RELIABILITY TESTS
- LIFE TEST SUMMARY

### **FAILURE RATE ESTIMATION**

### Introduction

This report contains reliability test results of various surface mount tantalum chip capacitors subjected to routine Monitoring Reliability Testing (MRT). The products used in this testing are all representative of manufacturing process for tantalum chip capacitors.

### Estimation Of Failure Rate

There are various methods used to estimate the field failure rate of tantalum chip capacitors. NIC uses the following equation to estimate the field failure rate:

$$\lambda = \lambda_0$$
 (V/V $_0$ )  $^3$  x 2  $^{(T-To)/10}$ 

 $\lambda$ : failure rate at operating condition (V = applied voltage, T = environmental temperature)  $\lambda_0$ : failure rate at rated condition (V<sub>0</sub> = rated voltage, T<sub>0</sub>= rated temperature)

Example, for a capacitor:

Rated:  $V_0 = 20V DC$ ,  $T_0 = 85^{\circ}C$ Operated: V = 5V DC,  $T = 45^{\circ}C$ 

Failure Rate: NTC-T / NTC-L / NTC-P: 1%/1000 hours at +85°C with 1.0Ω/V circuit resistance

If  $\lambda_0$  is equal to 1%/1000 hrs., the estimated failure rate is as follows:

 $\lambda = \lambda_0 (5/20)^3 \times 2^{(45-85)/10}$   $\lambda = \lambda_0 \times (1/64) \times (1/16)$   $\lambda = 0.001\% / 1000 \text{ hrs.}$  $\lambda = 10 \text{ FIT}$ 



### **DE-RATED OPERATION**

Recommended Operations (Standard Applications)

Circuit Resistance: ≥3.0Ω/V

Voltage Derating: 70% of Rated Working Voltage

Rated Voltage	Recommend Maximum Operating Voltage		
4.0VDC	2.8VDC		
6.3VDC	4.4VDC		
10VDC	7VDC		
16VDC	11.2VDC		
20VDC	14VDC		
25VDC	17.5VDC		
35VDC	24.5VDC		
50VDC	35VDC		

Recommended Operations (Low Impedance Circuit Applications)

Circuit Resistance: <3.0Ω/V

Voltage Derating: 33% of Rated Working Voltage

Rated Voltage	Recommend Maximum Operating Voltage		
4.0VDC	1.3VDC		
6.3VDC	2.1VDC		
10VDC	3.3VDC		
16VDC	5.3VDC		
20VDC	6.6VDC		
25VDC	8.3VDC		
35VDC	11.6VDC		
50VDC	16.5VDC		



# LIST OF RELIABILITY TESTS

TEST ITEM	SAMPLE SIZE
Visual & Mechanical Examination	8
DC Leakage (Initial)	20
Capacitance (Initial)	20
Dissipation Factor (Initial)	20
Impedance (Initial)	5
Solderability	5
Resistance To Solder Heat	12
Bond Strength Of The End Face Plating	12
Mounting	78/66/24
Adhesion	18
Rapid Change Of Temperature	18
Climatic Sequence	18
Damp Heat, Steady Heat	9
Endurance: 1. @ 85°C, Rated Voltage 2. @ 125°C, Derated Voltage	24
Characteristics At High & Low Temperatures	15
Surge: 1. @ 85°C, R.V. x 1.15 2. @125°C, D.V. x 1.15	6
Reverse Voltage (R.V. x -0.1, or - 3V)	6

### **LIFE TEST SUMMARY**

## High Temperature Operating Life (Endurance) Test Summary

This section summarizes the reliability test results for tantalum chip capacitors.. The failure rate prediction is based on 85°C high temperature life (endurance) test results.

# Failure Rate Prediction Based Upon Endurance Test Results

Period	Lot No	No. Of Devices	No. Of Failures	Accumulated Device Hours	Acceleration Factor	Equivalent Device Hours	Failure Rate 85°C
6/89 9/89	9F	72	0	144,000	1	144,000	
12/89 1/90	9J	72	0	144,000	1	144,000	
1/90 4/90	9M	72	0	144,000	1	144,000	
4/90 7/90	0C	72	0	144,000	1	144,000	
6/90 9/90	0F	72	0	144,000	1	144,000	
8/90 12/90	0J	72	0	144,000	1	144,000	
1/91 4/91	ОМ	72	0	144,000	1	144,000	
4/91 7/91	1C	72	0	144,000	1	144,000	
6/91 9/91	1F	72	0	144,000	1	144,000	
9/91 12/91	1J	72	0	144,000	1	144,000	
1/92 4/92	1M	72	0	144,000	1	144,000	
4/92 9/92	2C	72	0	144,000	1	144,000	
8/92 10/92	2F	72	0	144,000	1	144,000	
10/92 12/92	2J	72	0	144,000	1	144,000	
1/93 4/93	2M	72	0	144,000	1	144,000	
4/93 7/93	3C	72	0	144,000	1	144,000	
7/93 10/93	3F	72	0	144,000	1	144,000	

# Failure Rate Prediction Based Upon Endurance Test Results (continued)

Period	Lot No	No. Of Devices	No. Of Failures	Accumulated Device Hours	Acceleration Factor	Equivalent Device Hours	Failure Rate 85°C
10/93 12/93	3J	72	0	144,000	1	144,000	
1/94 4/94	3M	72	0	144,000	1	144,000	
4/94 7/94	4C	72	0	144,000	1	144,000	
7/94 10/94	4F	72	0	144,000	1	144,000	
10/94 12/94	4J	72	0	144,000	1	144,000	
1/95 4/95	4M	72	0	144,000	1	144,000	
5/95 7/95	5C	72	0	144,000	1	144,000	
7/95 10/95	5F	72	0	144,000	1	144,000	
10/95 12/95	5J	72	0	144,000	1	144,000	
11/95 1/96	5K	72	0	144,000	1	144,000	
2/96 4/96	6A	72	0	144,000	1	144,000	
2/96 4/96	6B	72	0	144,000	1	144,000	
4/96 8/96	6C	72	0	144,000	1	144,000	
5/96 8/96	6D	72	0	144,000	1	144,000	
8/96 10/96	6f	72	0	144,000	1	144,000	
8/96 10/96	6G	72	0	144,000	1	144,000	
11/96 2/97	6K	72	0	144,000	1	144,000	
11/96 3/97	6L	72	0	144,000	1	144,000	
2/97 4/97	7A	72	0	144,000	1	144,000	
2/97 5/97	7A	72	0	144,000	1	144,000	
4/97 7/97	7D	72	0	144,000	1	144,000	
5/97 8/97	7E	72	0	144,000	1	144,000	

# Failure Rate Prediction Based Upon Endurance Test Results (continued)

Period	Lot No	No. Of Devices	No. Of Failures	Accumulated Device Hours	Acceleration Factor	Equivalent Device Hours	Failure Rate 85°C
8/97 10/97	7G	72	0	144.000	1	144,000	
8/97 10/97	7H	72	0	144,000	1	144,000	
11/97– 2/98	7K	72	0	144,000	1	144,000	
12/97– 3/98	7M	72	0	144,000	1	144,000	
4/98- 6/98	8E	72	0	144,000	1	144,000	
10/98 – 12/98	8J	72	0	144,000	1	144,000	
1/99 – 3/99	8M	72	0	144,000	1	144,000	
Cumulativ Total	/e	3,312	0	6,624,000	1	6,624,000	0.0151%/ 1000 hrs.*

<sup>\*</sup> This estimated failure rate reflects acceleration factor used.